PCN Number: 20190923000.1						PCN D								
Title: Qualification of Hana as an alternate Assembly site for Select Devices in the DQN Package														
Customer Contact: PCN Manager Dept: Quality Services														
				n 23 20)20	Estimated Sample Date prov			provided at le request					
Change	Change Type:													
	embly Site	۵			Desigr	າ				Wafe	r Bum	n Site		
	embly Pro				Data S									
	embly Ma				Part number change Wafer Bum									
	hanical S		tion		Test Site				Ħ		Wafer Fab Site			
	king/Ship				Test Process			Ħ	Wafer Fab Materials					
	<u> </u>			<u> </u>					Wafe	afer Fab Process				
					PCN	Deta	ils	•		•				
Descrip	tion of C	hange:												
				annou	nce the	qualifi	cation of H	lan	a a	s an A	ddition	al Assembly		
site for t	he list of	devices	showi	n below	. Curre	ent asse	embly site	and	d M	laterial	differ	ences are as		
follows:														
						105	_							
					JCET				Hana					
		Compo			S#120402001600				SID#400194					
	Mold C	ompour	<u>nd</u>		S#120903003009 SI				SID#4	D#450176				
Reason	Reason for Change:													
Continui	Continuity of Supply													
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):														
None	•		•	•		, ,	•			, (1		<u>, </u>		
Anticipated impact on Material Declaration														
☐ No Impact to the ☐ Material Declarations or Product Content reports are driven														
	Material Declaration from production data and will be available following the													
	production release. Upon production release the revised													
	reports can be obtained at the site link below													
http://www.ti.com/quality/docs/materialcontentsearch.tsp							<u>earch.tsp</u>							
Changes to product identification resulting from this PCN:														
Assembly Site Assembly Site Origin			Origin ((22L) A) Assembly Country Code (23L)			3L)	Assembly City					
JCET JCE			Œ	CHN						Jiangyin				
HANA HNT			NT		THA					Ayutthaya				
Sample product shipping label (not actual product label)														

TEXAS INSTRUMENTS

MADE IN: Malaysia 2DC: 2Q:

MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04

OPT: ITEM:

5A (L)T0:39750



(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483SI2

(P) (2P) REV:

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

TLV75507PDQNR	TLV75512PDQNR	TLV75519PDQNR	TLV75528PDQNT	
TLV75507PDQNT	TLV75512PDQNT	TLV75519PDQNT	TLV75530PDQNR	
TLV75509PDQNR	TLV75515PDQNR	TLV75525PDQNR	TLV75530PDQNT	
TLV75509PDQNT	TLV75515PDQNT	TLV75525PDQNT	TLV75533PDQNR	
TLV75510PDQNR	TLV75518PDQNR	TLV75528PDQNR	TLV75533PDQNT	
TLV75510PDQNT	TLV75518PDQNT			



TI Information Selective Disclosure

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: TLV75550PDQNR	QB\$ Product Reference: <u>TLV75506PDQNR</u>	QBS Product Reference: TLV75550PDQNR	QBS Product Reference: <u>TLV75730PDRV</u>	QBS Product Reference: <u>TLV75733PDRV</u>	QBS Process Reference: <u>TLV62568DBV</u>	QBS Package Reference: <u>TLV70750PDQN</u>
AC	Autoclave 121C	96 Hours	-	-	-	-		3/231/0	1/77/0
ED	Electrical Characterization	Per Datasheet Parameters	Pass	Pass	Pass	-	Pass	Pass	-
EDR	EEPROM Data Retention, 170C	420 Hours	-	-	-	-	3/231/0	-	-
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	-	-	3/3000/0	-
HAST	Biased HAST, 110C/85%RH	264 Hours	1/77/0	-	1/77/0	-	-	-	-
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	-	-	3/231/0	3/231/0	3/231/0
HBM	ESD - HBM	3000 V	-	-	-	-	1/3/0	-	-
CDM	ESD - CDM	1500V	1/3/0	-	1/3/0	-	-	2/6/0	-
HTOL	Life Test, 150C	300 Hours	-	-	1/77/0	2/154/0	-	3/231/0	-
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	1/77/0	-	3/231/0	3/231/0	3/231/0
LU	Latch-up.	(per JESD78)	-	-	-	-	1/6/0	2/12/0	1/6/0
SD	Solderability	8 Hours Steam Age	-	-	-	-	-	-	2/44/0
TC	Temperature Cycle, -65/150C	500 Cycles	1/77/0	-	1/77/0	-	3/231/0	3/231/0	-
TC	Temperature Cycle, -65/150C	500 Hours	-	-	-	-	-	-	3/231/0
UHAST	Unbiased HAST, 110C/85%RH	264 Hours	1/77/0	-	-	-	-	-	-
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	1/77/0	-	-	-	-
UHAST	Unbiased HAST, 130C/85%RH	96 Hours	-	-	-	-	3/231/0	-	3/231/0
YLD	FTY and Bin Summary	Acceptable Yield	Pass	-	-	-	-	-	-

⁻ QBS: Qual By Similarity

⁻ Qual Devices qualified at LEVEL1-260C: TLV75550PDQNR, TLV75533PDQNR, TLV75506PDQNR, TLV75510PDQNR, TLV75515PDQNR, TLV75525PDQNR, TLV75530PDQNR. TLV75518PDQNR, TLV75528PDQNR, TLV75512PDQNR

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HT
- The following are equivalent
HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles
Quality and Environmental data is available at Tt's external Web site: http://www.ti.com/
Green/Pb-free Status:
Qualified Pb-Free(SMT) and Green

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